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March 2015

FDD86102LZ

N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 35 A, 22.5 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 22.5 m Ω at V_{GS} = 10 V, I_D = 8 A
- Max $r_{DS(on)}$ = 31 m Ω at V_{GS} = 4.5 V, I_D = 7 A
- HBM ESD protection level > 6 kV typical (Note 4)
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

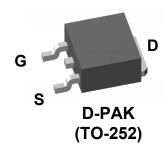


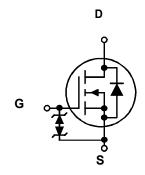
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

Applications

- DC DC Conversion
- Inverter
- Synchronous Rectifier





MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V_{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T _C = 25 °C		35	
I _D	-Continuous	T _A = 25 °C	(Note 1a)	8	Α
	-Pulsed			40	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	84	mJ
D	Power Dissipation	T _C = 25 °C		54	W
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	3.1	VV
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	40	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86102LZ	FDD86102LZ	D-PAK(TO-252)	13 "	16 mm	2500 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV_DSS	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25 °C		69		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μА
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ

On Characteristics (Note 2)

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.5	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-6		mV/°C
		V _{GS} = 10 V, I _D = 8 A		17.8	22.5	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$		23.2	31	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		31.1	40	1
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 8 A		31		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50.V.V 0.V	1157	1540	pF
Coss	Output Capacitance	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz	181	245	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	7.7	15	pF
R_q	Gate Resistance		0.6		Ω

Switching Characteristics

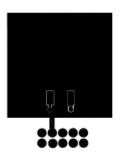
t _{d(on)}	Turn-On Delay Time		6.6	14	ns
t _r	Rise Time	V _{DD} = 50 V, I _D = 8 A,	2.3	10	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω	20	32	ns
t _f	Fall Time		2.3	10	ns
Q_{g}	Total Gate Charge	V _{GS} = 0 V to 10 V	18	26	nC
Q_g	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} V_{DD} = 50 \text{ V},$	8.7	13	nC
Q _{gs}	Gate to Source Gate Charge	I _D = 8 A	2.7		nC
Q_{gd}	Gate to Drain "Miller" Charge		2.4		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 8 \text{ A}$ (Note 2	()	0.82	1.3	V
	Source to Drain Diode 1 diward voltage	$V_{GS} = 0 \text{ V}, I_S = 2.6 \text{ A}$ (Note 2	()	0.75	1.2	v
t _{rr}	Reverse Recovery Time	L = 9 A di/dt = 100 A/vo		43	70	ns
Q _{rr}	Reverse Recovery Charge	- I _F = 8 A, di/dt = 100 A/μs		43	70	nC

Notes:

 R_{0JC} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



a. 40 °C/W when mounted on a 1 in² pad of 2 oz copper.



 b. 96 °C/W when mounted on a minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.

^{3.} Starting T_J = 25 $^{\circ}C,\,L$ = 1 mH, I_{AS} = 13 A, V_{DD} = 90 V, V_{GS} = 10 V.

^{4.} The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

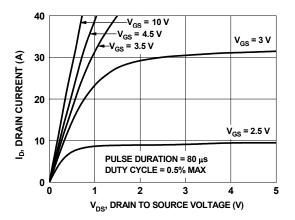


Figure 1. On-Region Characteristics

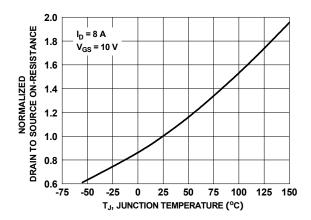


Figure 3. Normalized On-Resistance vs Junction Temperature

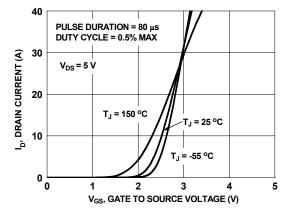


Figure 5. Transfer Characteristics

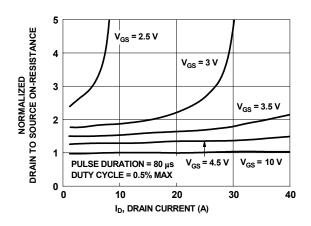


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

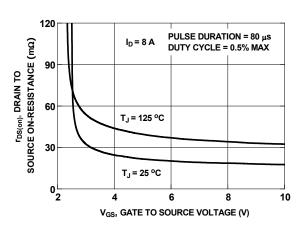


Figure 4. On-Resistance vs Gate to Source Voltage

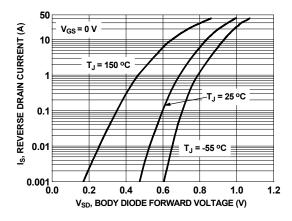


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 $^{\circ}$ C unless otherwise noted

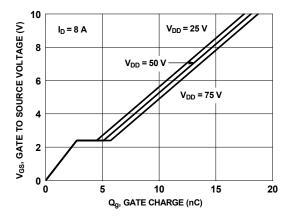


Figure 7. Gate Charge Characteristics

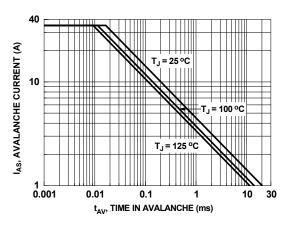


Figure 9. Unclamped Inductive Switching Capability

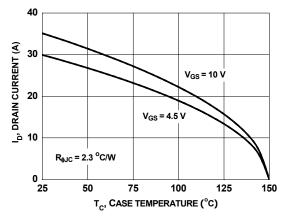


Figure 11. Maximum Continuous Drain Current vs Case Temperature

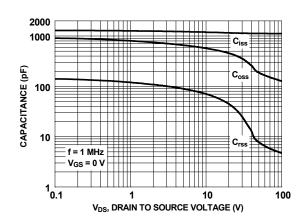


Figure 8. Capacitance vs Drain to Source Voltage

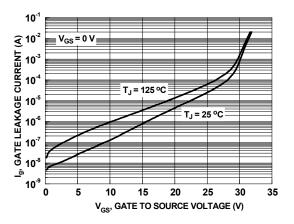


Figure 10. Gate Leakage Current vs Gate to Source Voltage

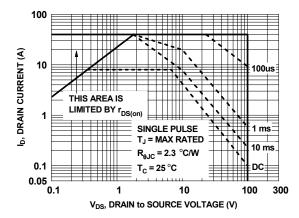


Figure 12. Forward BiasSafe Operating Area

Typical Characteristics $T_J = 25$ °C unless otherwise noted

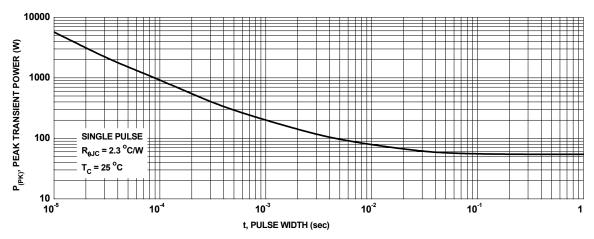


Figure 13. Single Pulse Maximum Power Dissipation

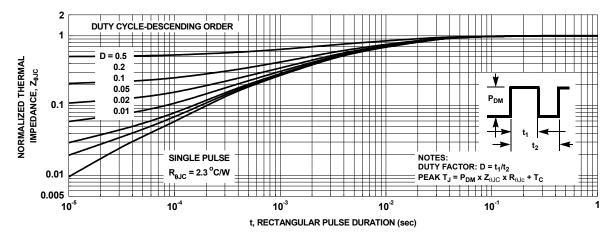


Figure 14. Junction-to-Case Transient Thermal Response Curve



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